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Application/Control No.	Applicant(s)/Patent under Reexamination
09/725,674	HIRANO ET AL.
Examiner	Art Unit
Minh Dieu Nguyen	2137

SEARCHED				
Class	Subclass	Date	Examiner	
713	176-179, 201	6/8/2005	MDN	
705	51	6/8/2005	MDN	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
713	176, 201	6/8/2005	MDN	
705	51	6/8/2005	MDN	
	-1-			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventor name search on EAST (US-PAT; US-PG-PUB; EPO; JPO; DERWENT; IBM-TDB)	6/8/2005	MDN		
EAST search (US-PAT; US-PG-PUB; EPO; JPO; DERWENT; IBM-TDB)	6/8/2005	MDN		